Mapping

Provides order level fulfillment and tracking

Overview

Some manufacturing industries such as semiconductor, PCB and SMT, require that the system keeps track of units inside a two-dimensional surface. In some cases, the surface is divided into uniform regular rectangles in the form of a matrix while in other cases the shape, position, and orientation of each unit within the two-dimensional space can be very different.

The Mapping module provides support for two-dimensional structures that can be linked and integrated with material tracking for the purposes of tracking quantities, defects, or other sub-material level properties.
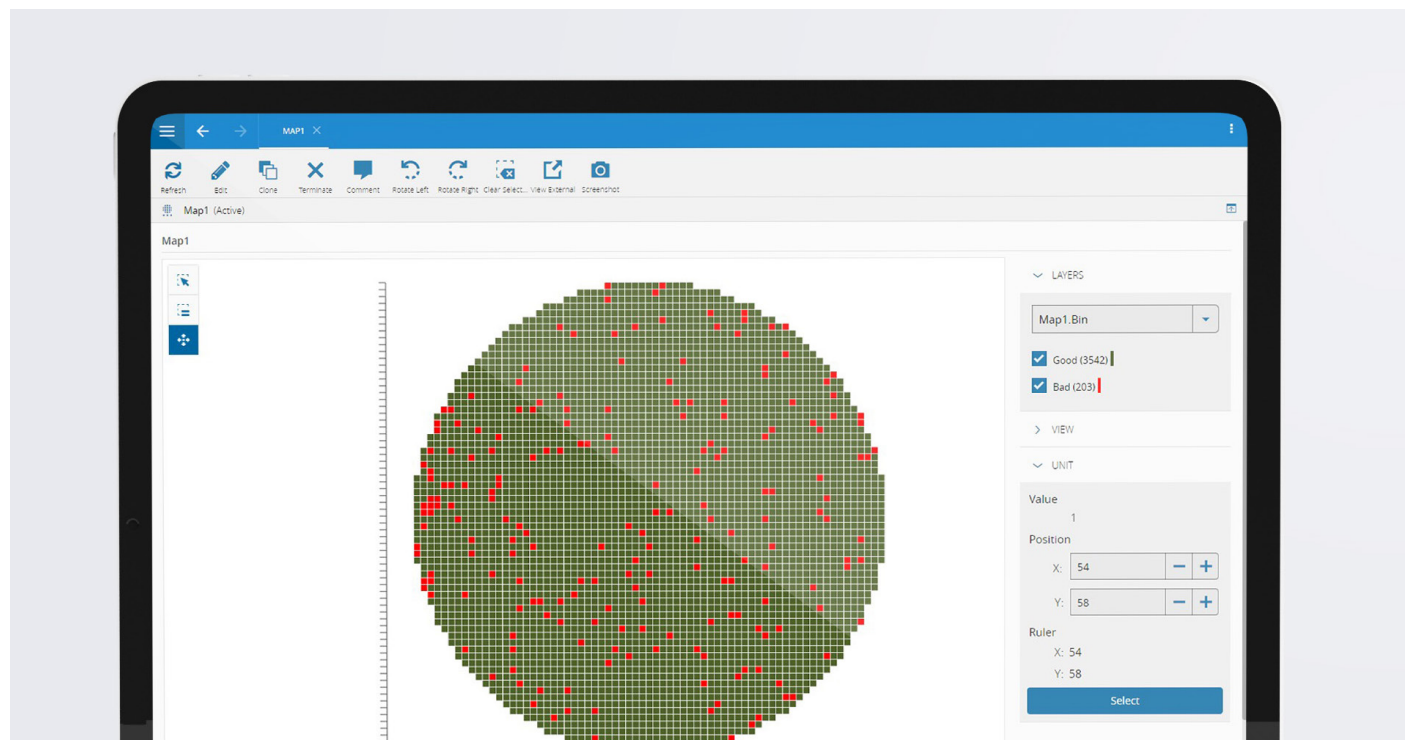

Figure 1 Map viewer example (regular map)

Critical manufacturing 11.2

contact@criticalmanufacturing.com · www.criticalmanufacturing.com

Key Features

- Support for multiple Map Definitions that act as templates from which maps can be created.
- Support for regular and irregular layout (with different shapes, sizes and orientations) map structures.
- Support for multiple layers per map and multiple maps per material.
- Support for map regions.
- Native support for SEMI G85 and E142 map structures.
- Interactive visualization of maps, including flip, zoom, rotation, and filters.
- Support for editing E142 bin code maps.
- Support for automatic merge of multiple maps into a master map.

- Support for merged maps, in which a master map aggregates the results of multiple individual maps.
- Native integration with Material Tracking so that when recording losses in the map, the Material quantity is automatically synchronized.
- Capability to define and apply Substrate Masks.
- Capability to search for a E142 map based on Substrate, Carrier, Lot, Alias or Device.
- E142 die-level forward and backward traceability.
- Capability to define and apply Substrate Masks.
- Capability to convert E142 bin codes when downloading to or uploading from equipment.

Benefits

- Spatial tracking of units, including their defects
- Die-level traceability

- Automatic material quantity synchronization with the map good units
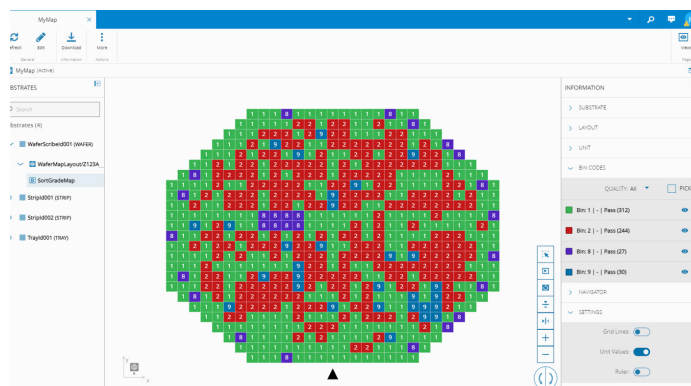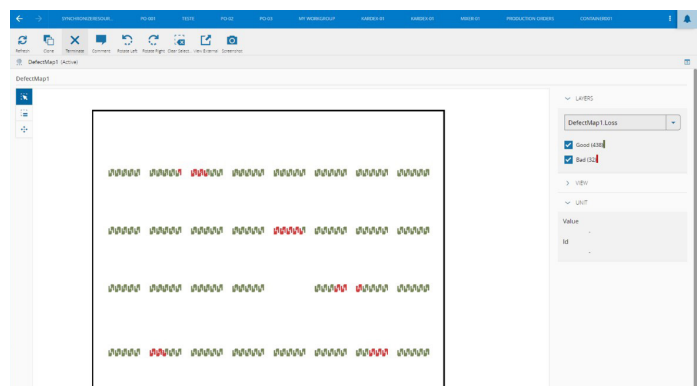- Die-level traceability

Figure 2 Map viewer example (E142 map)

Figure 3 Map viewer example (irregular map)

Critical manufacturing 11.2

contact@criticalmanufacturing.com · www.criticalmanufacturing.com